

Search Notes

Application/Control No.

10/824,824

Examiner

Brad Y. Chin

Applicant(s)/Patent under
Reexamination

SMITH ET AL.

Art Unit

1744

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------|-----------|----------|
| 422 | 5 | 4/22/2005 | BYC |
| 431 | 324 | 4/22/2005 | BYC |
| 431 | 343 | 4/22/2005 | BYC |
| 362 | 171 | 4/22/2005 | BYC |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------|-----------|----------|
| Same | As Above | 4/22/2005 | BYC |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
|---|-----------|------|
| Consultation with Jastrzab, Krisanne & Kim, Sun (John). | 4/22/2005 | BYC |
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